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Application/Control No.		
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Applicant(s)/Patent under Reexamination
YIP ET AL.

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SEARCHED			
Class	Subclass	Date	Examiner
375	222, 354	10/24/2006	JATM

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NO (INCLUDING SEARCE)
	DATE	EXMR
EAST	10/24/2006	JATM
IDS Flag Clearance	10/24/2006	JATM
Inventor search	10/24/2006	JATM
Google	10/24/2006	JATM
Scirus	10/24/2006	JATM
IEEE	10/24/2006	JATM
101 Panel	10/24/2006	JATM